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STATEMENT BY APPLICANT	First Inventor	PHILIPPOU
STATEMENT DI ATTECANT	Art Unit	1745
	Examiner	
Sheet <u>1</u> of <u>1</u>	Docket #	P08753US00/MP

		U.S. PATE	NT DOCUMENTS	
Exam. Initial*	Document No. Number - Kind	Publ. Date MM-DD-YYYY	Name Patentee or Applicant	Relevance Passages/Figs.
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Exam. Initial*	Country-Number-Kind	Publ. Date MM-DD-YYYY	Name Patentee or Applicant	Relevance Passages/Figs.	Trans- lation

	NON PATENT LITERATURE DOCUMENTS	
Exam. Initial*	Include NAME of the author (in CAPS), Title of Article/Item, Date, Page(s), Volume-Issue No., Publisher, City and/or Country where published	Trans- lation
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Examiner Signature /Jeff Aftergut/ Date Considered 09/29/2009

^{*} Examiner: Initial if considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.